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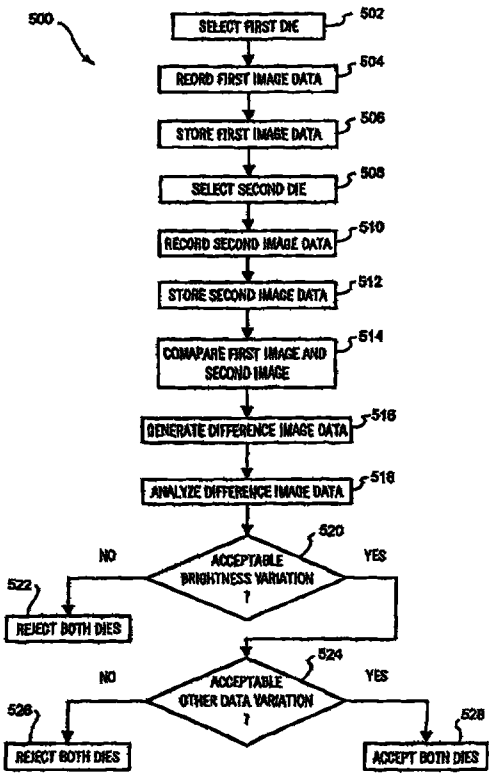
(54) Title: SYSTEM AND METHOD FOR SELECTION OF A REFERENCE DIE

(57) Abstract

A system for selecting reference die images, such as for use with a visual die inspection system, is provided. The system includes a die image comparator, which compares (514) a first die image (504) to a second die image (510) in order to create a difference image (516) that contains only the difference between the two die images. The system also includes a difference image analysis system that receives data from the die image comparator. The difference image analysis system analyzes the difference image (518) and determines whether there are any features of the difference image (520, 524) that indicate that either the first die image or the second die image should not be used as a reference die image.